PROCEEDINGS OF SPIE

Modeling Aspects in Optical Metrology IX

Bernd Bodermann Karsten Frenner Editors

26–28 June 2023 Munich, Germany

Sponsored and Published by SPIE

Volume 12619

Proceedings of SPIE 0277-786X, V. 12619

SPIE is an international society advancing an interdisciplinary approach to the science and application of light.

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Please use the following format to cite material from these proceedings: Author(s), "Title of Paper," in *Modeling Aspects in Optical Metrology IX*, edited by Bernd Bodermann, Karsten Frenner, Proc. of SPIE 12619, Seven-digit Article CID Number (DD/MM/YYYY); (DOI URL).

ISSN: 0277-786X

ISSN: 1996-756X (electronic)

ISBN: 9781510664470

ISBN: 9781510664487 (electronic)

Published by

SPIE

P.O. Box 10, Bellingham, Washington 98227-0010 USA Telephone +1 360 676 3290 (Pacific Time) SPIE.ora

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